

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANTS : Hideo TODOKORO, et al.  
SERIAL NO. : (Cont. of 09/486,042)  
FILED : (Herewith)  
FOR : SCANNING ELECTRON MICROSCOPE  
GROUP ART UNIT : 2881 (Anticipated)  
Examiner : K. T. Nguyen (Anticipated)

COMMISSIONER FOR PATENTS  
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**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97**

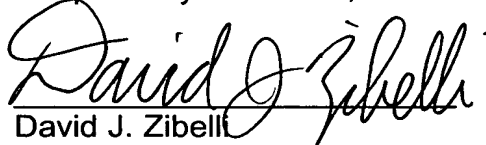
S I R:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all of the references have already been considered by the Examiner in application number 09/486,042, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

  
David J. Zibelli  
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Date: 04 November 2003

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**FORM PTO-1449****INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT(S)**

Atty Docket No. : 1743/227  
 Serial No. :  
 Inventors : H. Todokoro et al.  
 Filed :  
 Group Art Unit : 2881 (Anticipated)  
 Examiner : K.T. Nguyen (Anticipated)

**U.S. PATENT DOCUMENTS**

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/ Subclass</u>	<u>Filing Date</u>
	5,872,358	02/16/99	TODOKORO et al.	250/310	
	6,025,593	02/15/00	SUZUKI et al.	250/310	
	4,922,097	05/01/90	TODOKORO et al.	250/310	
	5,517,028	05/14/96	ITO et al.	250/310	
	6,037,589	03/14/00	YONEZAWA et al.	250/310	
	5,389,787	02/14/95	TODOKORO et al.		
	5,424,541	06/23/95	TODOKORO et al.		
	5,608,218	03/04/97	SATO et al.		

**FOREIGN PATENT DOCUMENTS**

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/ Subclass</u>	<u>Translation</u>	
					<u>Yes</u>	<u>No</u>
	59-001916	01/11/84	Japan		ABS.	
	60-061238	03/26/85	Japan		ABS.	
	9-171791	06/30/97	Japan			X
	5-266855	10/15/93	Japan			X
	61-220259	09/30/86	Japan			X
	6-139985	05/20/94	Japan			X
	7-192679	07/28/95	Japan			X
	60-146439	08/02/85	Japan			X

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.